

Form PTO-1449  
(MODIFIED)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.

039153-0405 (F0945)

SERIAL NO.

09/820,143

## INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

APPLICANT

Uzodinma Okoroanyanwu et al.

FILING DATE

03/28/2001

GROUP ART UNIT

2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
UM.E.	A1	6,197,687	3/06/2001	Buynoski			
UM.E.	A2	5,994,225	11/30/99	Liu et al.			
UM.E.	A3	5,876,903	3/02/99	Ng et al.			
UM.E.	A4	5,468,595	11/21/1995	Livesay			

## FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

UM.E.	A5	Chiong K.G. et al. "Resist Contrast Enhancement in High Resolution Electron Beam Lithography", Journal of Vacuum Science and Technology: Part B, American Institute of Physics, New York, US, vol. 7, no. 6.
UM.E.	A6	Patent Abstracts of Japan, vol 1999, no. 09, 30 July 1999 (1999-07-30) & JP 11 097328 A (Toshiba Corp), 9 April 1999 (1999-04-09) abstract

EXAMINER

M. El-Shammaa

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7.25.02

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EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
U.M.E.	A1	6,232,048	5/15/2001	Buynoski et al.			
U.M.E.	A2	6,197,687	3/6/01	Buynoski			
U.M.E.	A3	6,110,837	8/29/00	Linliu et al.			
U.M.E.	A4	5,876,903	3/2/99	Ng et al.			
U.M.E.	A5	5,468,595	11/21/95	Livesay			
U.M.E.	A6	3,997,367	12/14/1976	Yau			

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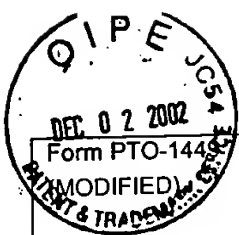
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	<b>APPLICANT</b> Uzodinma Okoroanyanwu et al.	
	<b>FILING DATE</b> 03/28/2001	<b>GROUP ART UNIT</b> 2878

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CM.E	A1	6,420,097	07/16/2002	Pike et al.	430	313	
CM.E	A2	6,395,447	05/28/2002	Ishii et al.	430	191	
CM.E	A3	6,358,670	03/19/2002	Wong et al.	430	296	
CM.E	A4	6,319,655	11/20/2001	Wong et al.	430	311	
CM.E	A5	6,200,903	03/13/2001	Oh et al.	438	705	
CM.E	A6	6,174,818	01/16/2201	Tao et al.	438	733	
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CM.E	A9	4394,211	07/19/1983	Uchiyama et al.	156	628	

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		09/819,342		Shields et al			03/28/01
		09/819,343		Gabriel et al			03/28/01
		09/819,344		Okoroanyanwu et al			03/28/01
		09/819,552		Gabriel et al			03/28/01
		09/819,692		Okoroanyanwu et al			03/28/01
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		6,103,457	08/15/00	Gabriel	430	318	
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		5,003,178	03/26/91	Livesay	250	492.300	

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		Livesay, W. R., "Large-area electron-beam source," Journal of Vacuum Science & Technology B, Vol. 11, No. 6, Nov./Dec. 1993, pp. 2304-2308, American Vacuum Society
		Yang, J. J. et al, "Electron Beam Processing for Spin-on Polymers and its Applications to Back-End-of-Line (BEOL) Integration," Materials Research Society Symposium Proceedings, Vol. 511, 1998, pp. 49-55, Materials Research Society
		Ross et al, "Plasma Etch Characteristics of Electron Beam Processed Photoresist," The Society of Photo-Optical Instrumentation Engineers, Vol. 2438, 1995, pp. 803-816, SPIE-The International Society for Optical Engineering
		Grün, Von A. E., "Lumineszenz-photometrische Messungen der Energieabsorption im Strahlungsfeld von Elektronenquellen Eindimensionaler Fall in Luft," Zeitschrift für Naturforschung, Vol. 12a, 1957, pp. 89-95, Publisher: Zeitschrift für Naturforschung; full English Translation attached (11 pgs.)

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